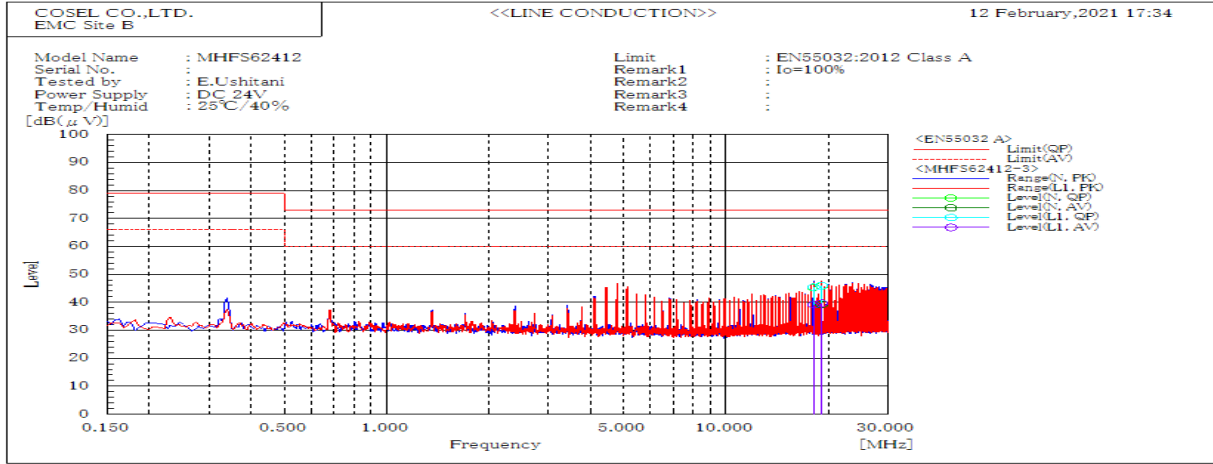
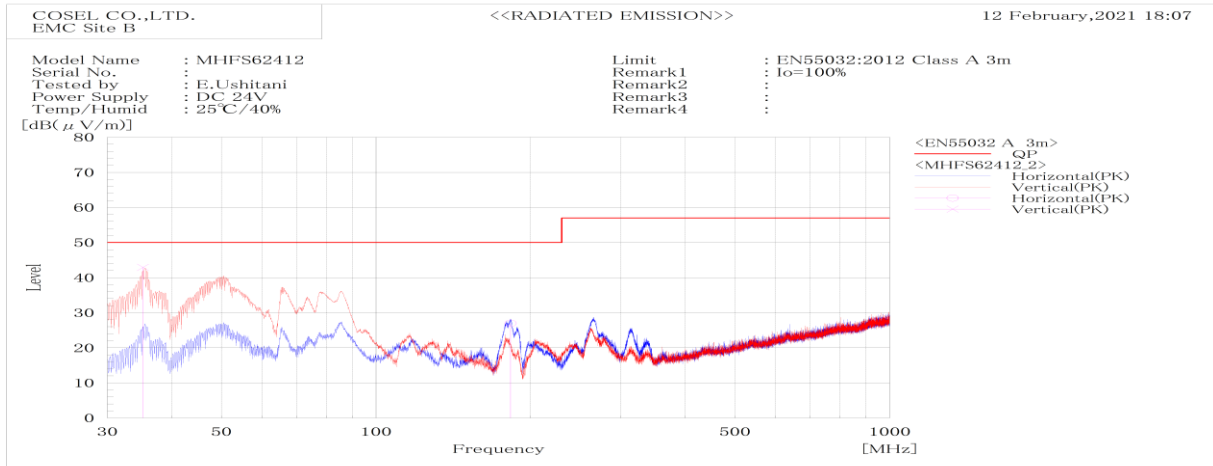


DATA SHEET		Date	05-Nov-21
Model	MHFS62412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



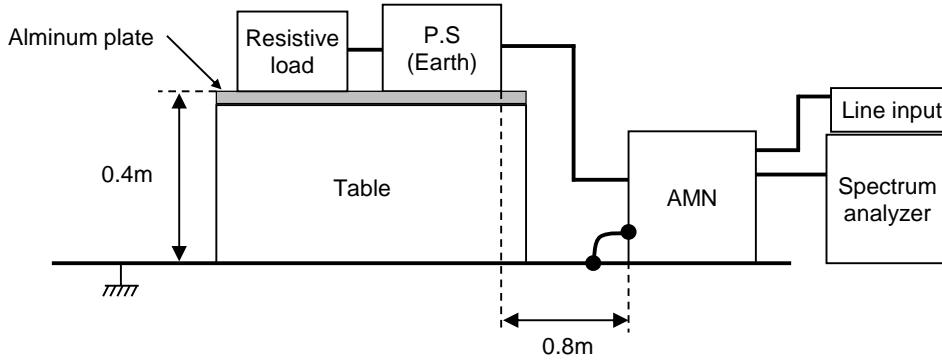
Frequency MHz	Line	Level		Limit		Margin		Pass/Fail	Remark
		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
19.128	L1	46	39.7	73	60	27	20.3	Pass	
18.107	L1	45.5	39.2	73	60	27.5	20.8	Pass	
19.123	N	45.8	39.2	73	60	27.2	20.8	Pass	
18.105	N	45.3	39.3	73	60	27.7	20.7	Pass	



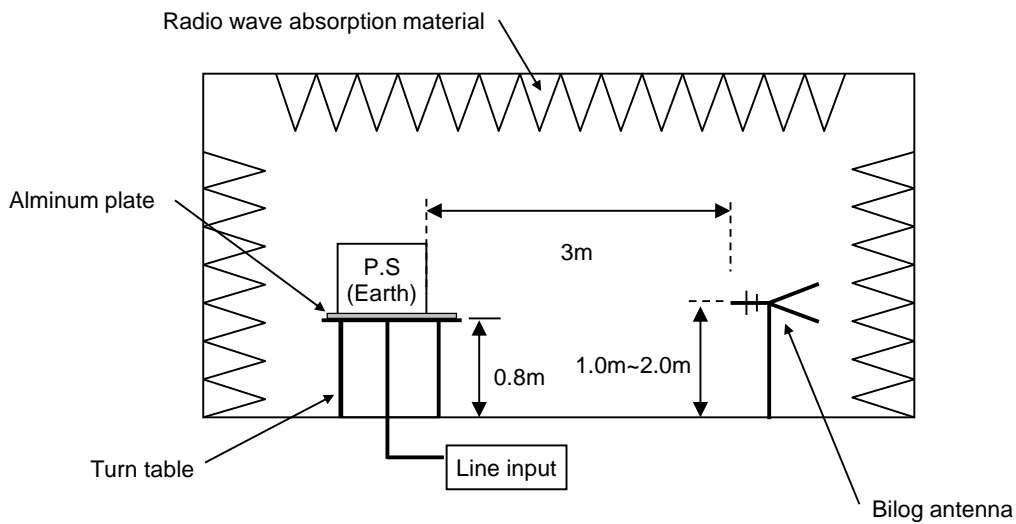
Frequency MHz	Polarization	Stability	Level		Limit		Margin		Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m)		dB(uV/m)		dB					
			QP	QP	QP	QP	QP	QP				
182.753	H	Stable	27	50	23	Pass	199.7	346.4				
35.19	V	Stable	42.9	50	7.1	Pass	101.5	282.7				

DATA SHEET		Date	05-Nov-21
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission

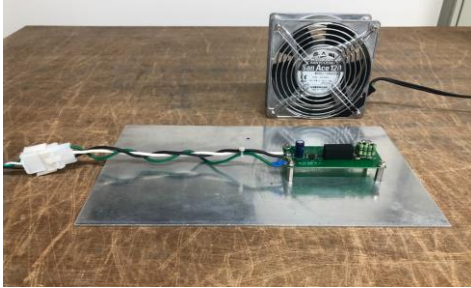


Conditions

Test : EMI
 Model Name: MHFS6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

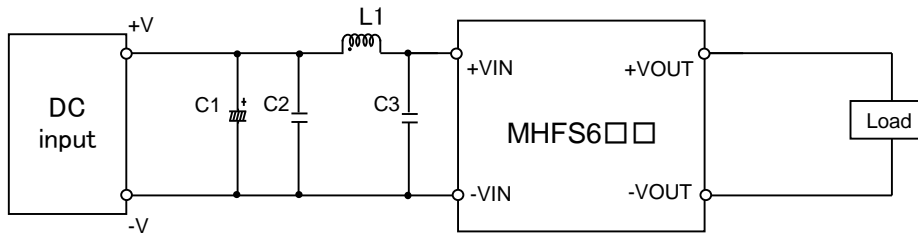


Fig.1 Testing circuitry

C1 :	MHFS612□□	50V 100 μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFS624□□	-
	MHFS648□□	-
C2 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFS612□□	25V 10 μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFS624□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFS648□□	100V 2.2 μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFS612□□	2600mA 2.2 μ H Inductor(LQH5BPN2R2NT0 MURATA MANUFACTURING)
	MHFS624□□	1600mA 10 μ H Inductor(LQH5BPN100MT0 MURATA MANUFACTURING)
	MHFS648□□	1050mA 22 μ H Inductor(LQH5BPN220MT0 MURATA MANUFACTURING)